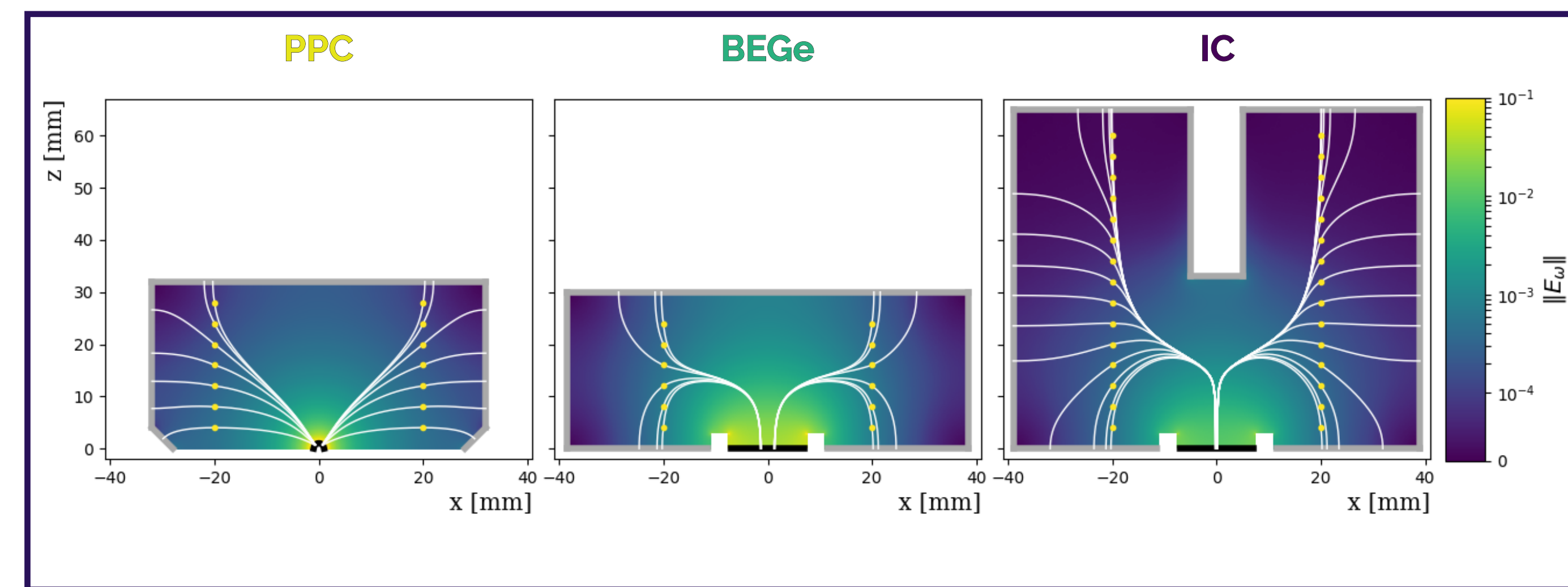


Modeling the collective motion of charge carriers in Ge semiconductor detectors

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1. Introduction

- Time profile of the signal in germanium detectors reveals information on the topology of the event
- On a typical event, millions of charge carriers are generated inside the detector as one or multiple clusters
- Collective effects deform each cluster and, in turn, the signal shape
- Study these effects with SigGen⁶ software and their impact on the event discrimination capabilities, with focus on neutrinoless double-beta decay experiments

2. Modeling Germanium Detectors

- Signal formation described by Shockley-Ramo theorem^{1,2}:

$$I(t) = q \mathbf{v}(r(t)) \cdot \mathbf{E}_w(r(t))$$

- Modeling in germanium -> development of three geometries used in present and future double-beta decay experiments:

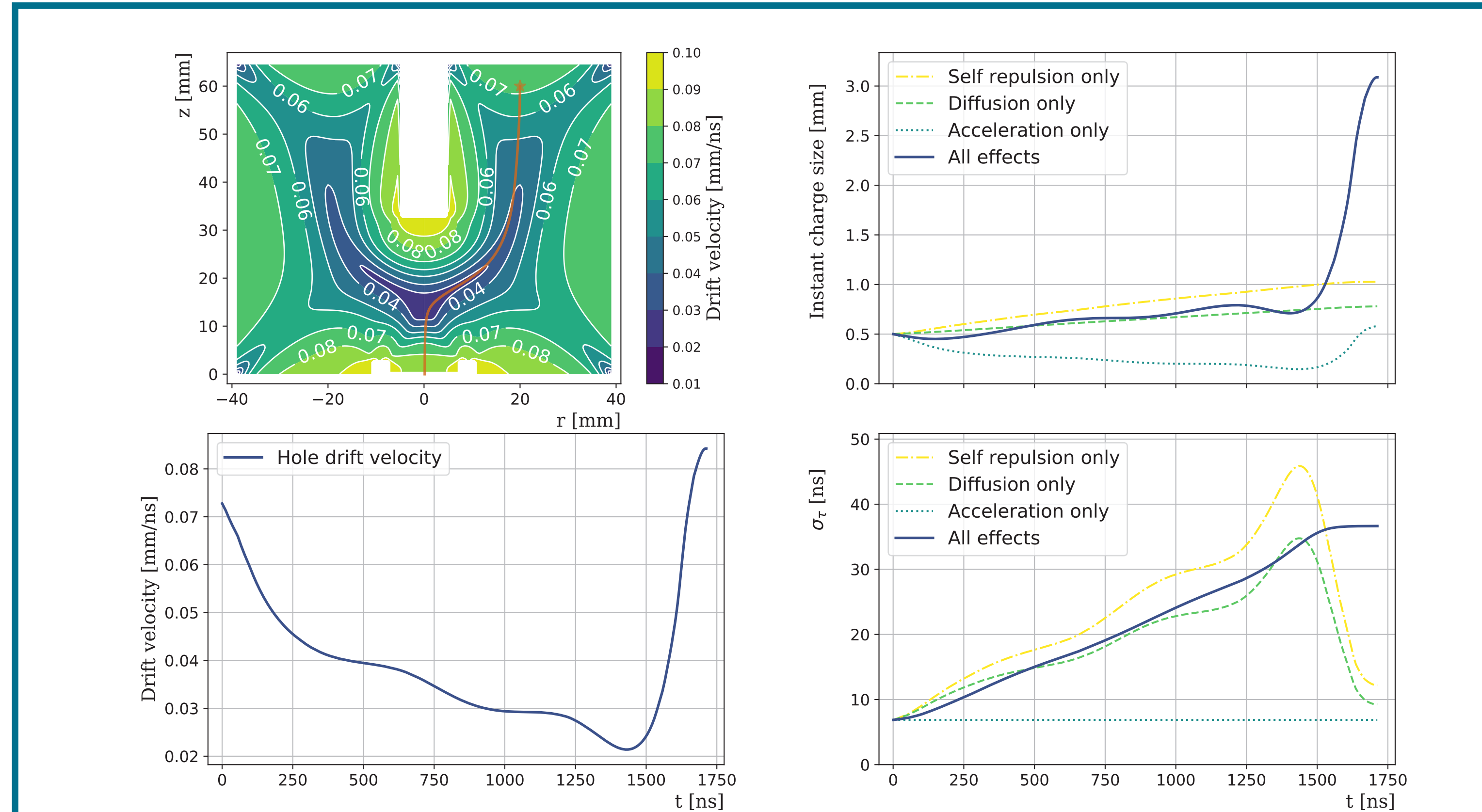
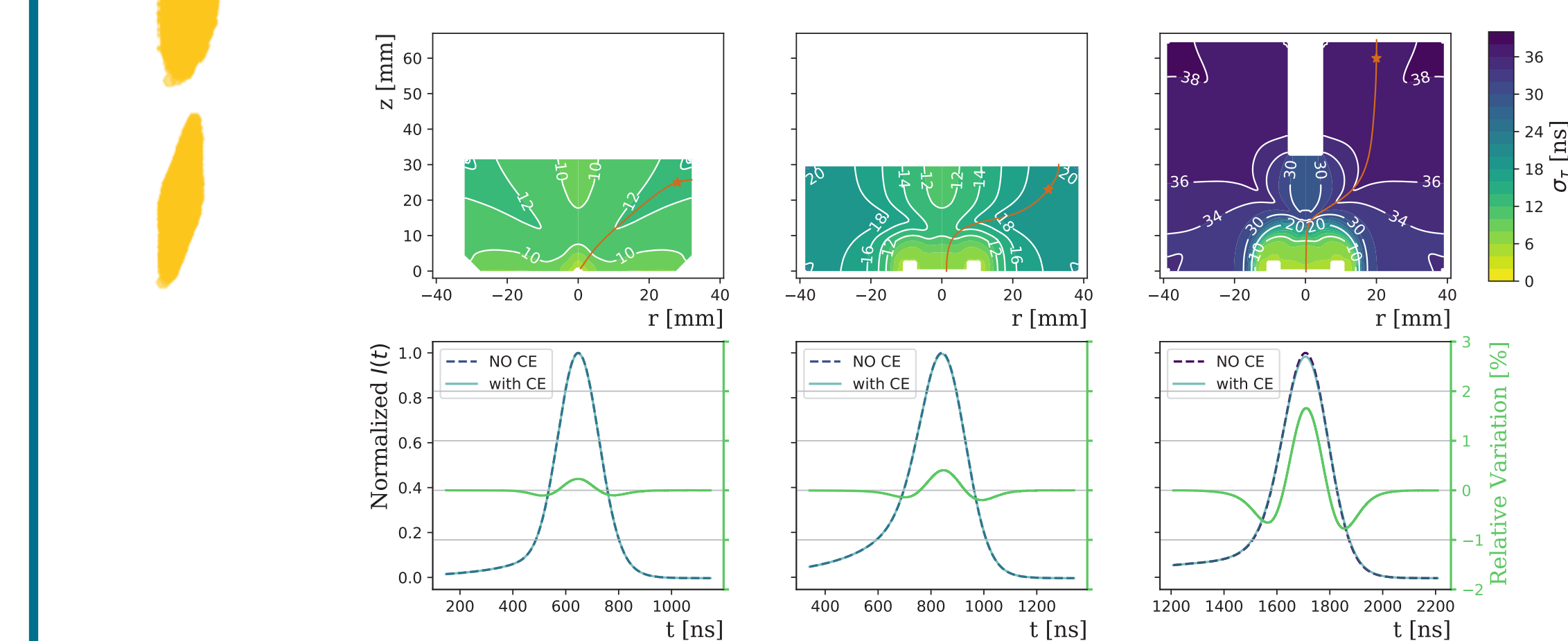
- P-type Point-Contact (PPC)³
- Broad Energy Germanium (BEGe)⁴
- Inverted Coaxial (IC)⁵

- All geometries developed to create high E_w close to readout electrode

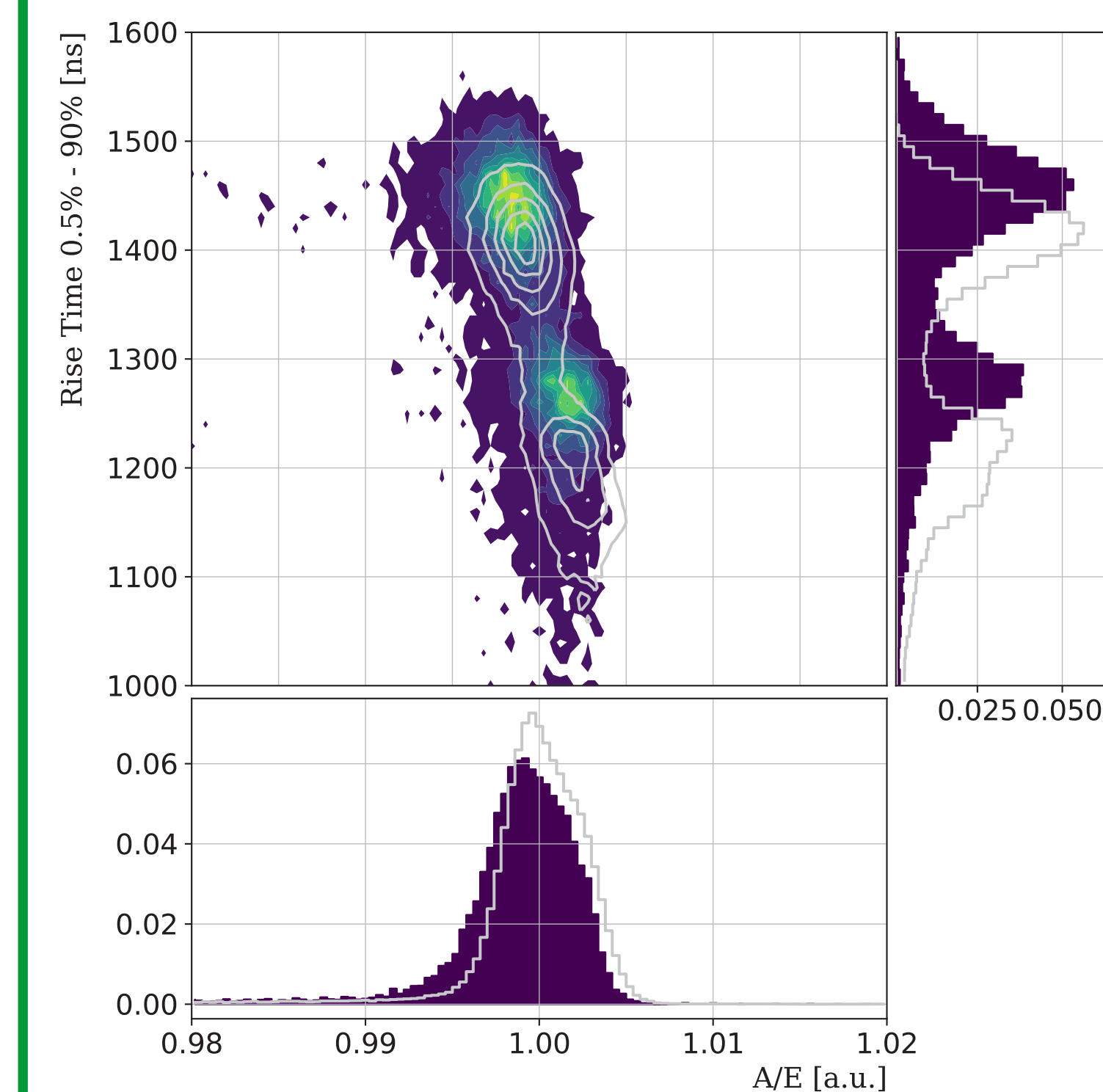
- Signal degeneracy
- IC exhibits drift paths which are double the length as for BEGes and PPCs

3. Collective motion of charge carriers

- Informations on collective effects in $q \rightarrow g(x(t))$
- What deforms the signal shape:
 - Initial cluster size
 - determines initial $g(x(0))$
 - Accelerations
 - acceleration -> enlargement
 - deceleration -> shrinkage
 - Coulomb self repulsion
 - always enlarges cluster
 - Stochastic diffusion
 - always enlarges cluster
- Interplay of effects gives deformation of cluster in time
- Describe through new parameter σ_r
- The bigger σ_r , the lower $I(t)$ -> relevant for IC

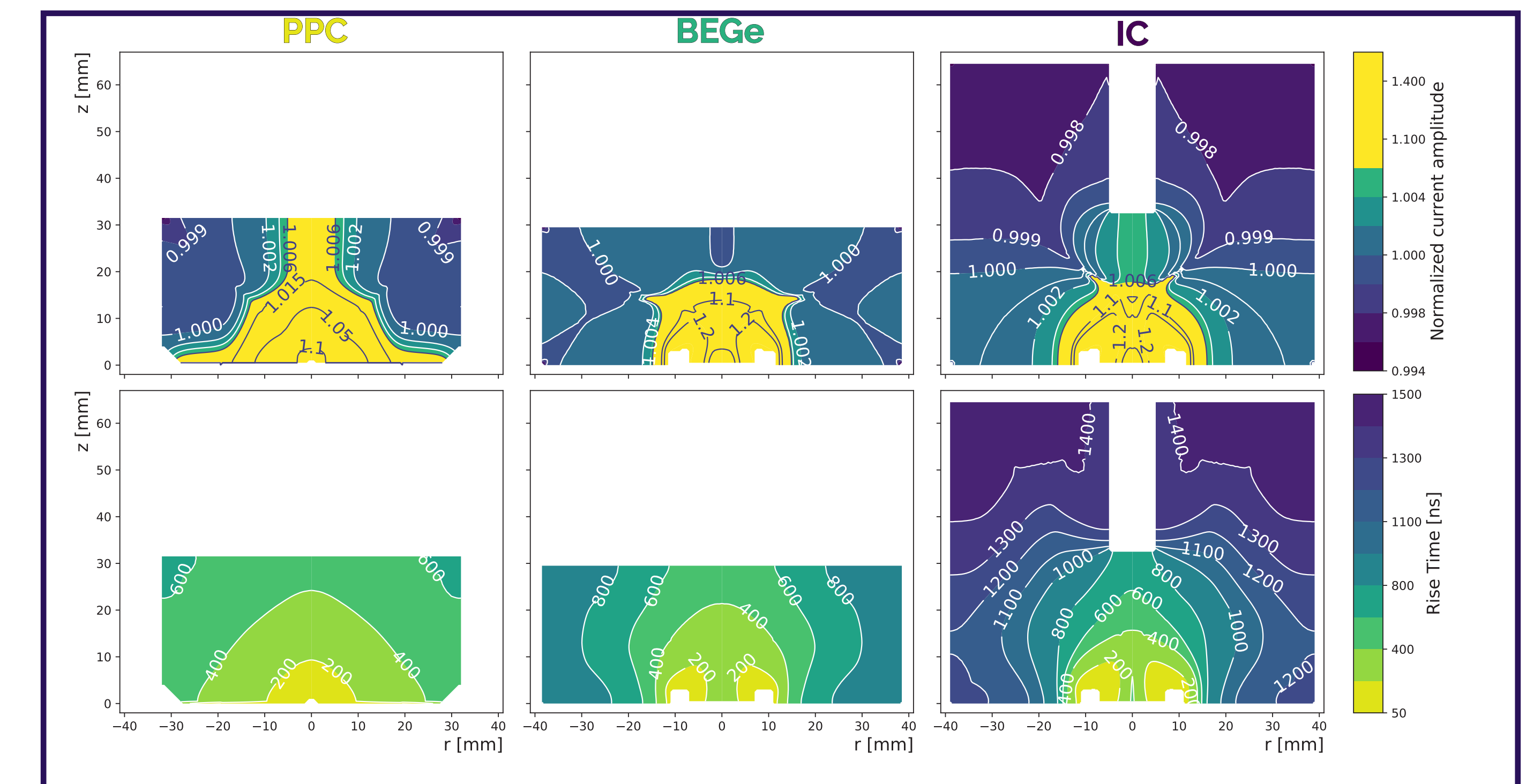


4. Impact on neutrinoless double-beta decay



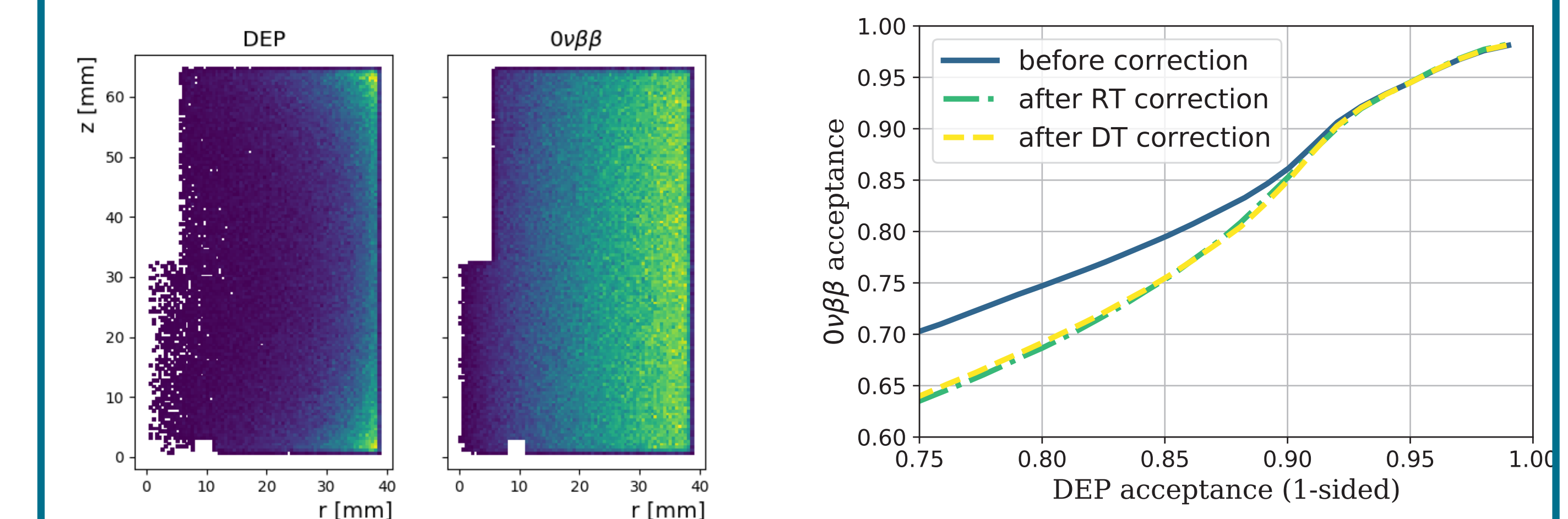
- Maximum of the current $I(t)$ -> Pulse Shape Discrimination (PSD) parameter (A/E^4) in neutrinoless double-beta decay experiments
- Collective effects bring an undesired position dependence of A/E
 - Longer drift path -> lower A/E
- Impact on discrimination capabilities?
 - Test in terms of:
 - $0\nu\beta\beta$ acceptance
 - background rejection
- Investigated correction based on drift path to restore position independence
- Simulations validated by experimental data

Event class	Simulations				Data		
	Standard	IC	RT corr	BEGe[19, 22]	IC (this work)	BEGe [10, 22]	Standard
^{208}Tl DEP	90.00 (8)	90.08 (8)	90 (1)	90 (1)	90.1 (8)	90.1 (8)	90 (1)
^{208}Tl SEP	5.1 (3)	5.8 (3)	8 (1)	8 (1)	5.0 (3)	5.3 (3)	5.5 (6)
^{208}Tl FEP	7.4 (1)	8.1 (1)	12 (2)	12 (2)	7.64 (5)	7.92 (5)	7.3 (4)
CC @ $Q_{\beta\beta}$ (^{208}Tl)	45.1 (3)	46.7 (3)	42 (3)	42 (3)	32.3 (2)	33.1 (2)	34 (1)
CC @ $Q_{\beta\beta}$ (^{214}Bi)	20.3 (4)	21.8 (4)	-	-	-	-	21 (3)
$0\nu\beta\beta$	86.07 (6)	85.47 (6)	88 (2)	88 (2)	-	-	-



5. Outlook

- Detector volumes keep on increasing
 - Impact of collective effects might get stronger
 - Background composition changes with geometry
 - Possibility to tune PSD cut to increase $0\nu\beta\beta$ acceptance
- Explored impact of electronics noise on PSD in IC
- Explored impact of collective effects in longer IC detectors



6. Conclusions

- Discussed collective effects in germanium detectors and impact on signal formation
- Determined that collective effects are relevant for long drift paths
- Checked impact of collective effects on IC discrimination capabilities
- Validated simulation with experimental data
- Performances of IC are suitable for search for neutrinoless double beta decay

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